

OptiMOS[™]3 Power MOS Transistor Chip

Туре	V(BR)DSS	R _{DS(on)}	Die size	Thickness
IPC26N12NR	120 V	4.8 m $\Omega^{2)}$	6.0 * 4.36 mm ²	250 μm

DESCRIPTION

- N-channel enhancement mode
- For additional characteristic and max ratings refer to the datasheet of IPP048N12N3 G¹⁾
- AQL 0.65 for visual inspection according to failure catalogue
- Electrostatic Discharge Sensitive Device according to MIL-STD 883C
- Die bond: soldered or glued
- Backside metallization: NiV system
- Frontside metallization: AISi system
- Passivation: nitride (only on edge structure)

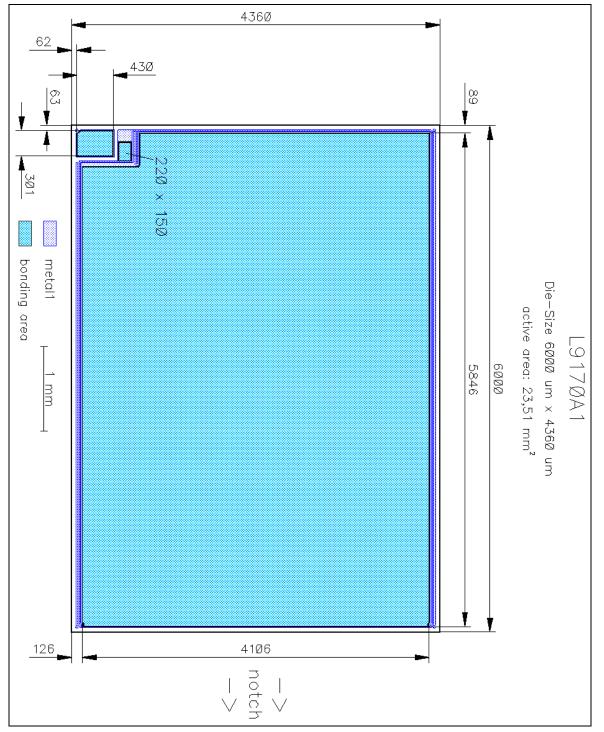
Electrical Characteristics on Wafer Level

at $T_j = 25 \text{ °C}$, unless otherwise specified.

Parameter	Symbol	Value			Unit	Conditions
		min.	typ.	max.		
Drain-source breakdown voltage	V(BR)DSS	120	-	-	V	$V_{GS} = 0V$
						I _D = 1 mA
Gate threshold voltage	V _{GS(th)}	2	-	4	V	$V_{DS} = V_{GS}$
						I _D = 230 μA
Zero gate voltage drain current	I _{DSS}	-	0.1	1	μA	$V_{GS} = 0V$
						V _{DS} = 100 V
Gate-source leakage current	I _{GSS}	-	1	100	nA	V _{GS} = 20 V
						$V_{DS} = 0 V$
Drain-source on-resistance	R _{DS(on)}	-	3.2 ⁴⁾	100 ³⁾	mΩ	V _{GS} = 10 V
						I _D = 2.0 A
Reverse diode forward on-voltage	V _{SD}	-	1.0	1.2	V	V _{GS} =0 V
						I _F = 1 A
Internal gate resistance	R _G	-	2	-	Ω	
Additional gate resistor	R _{Gadd}		16		Ω	
Avalanche energy, single pulse	E _{AS}	-	45 ⁵⁾	-	mJ	I _D = 30 A, <i>R</i> _{GS} =25Ω



Chip-Layout:



¹⁾ IPP048N12N3 G dynamic characterization does not include the internal added Rg

²⁾ packaged in a P-TO220-3-1 (see ref. product)

³⁾ limited by wafer test-equipment

 $^{\rm 4)}$ typical bare die $R_{\rm DS(on)};\,V_{\rm GS}{=}10V$

⁵⁾ Wafer tested. For general avalanche capability refer to the datasheet of IPP048N12N3 G

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